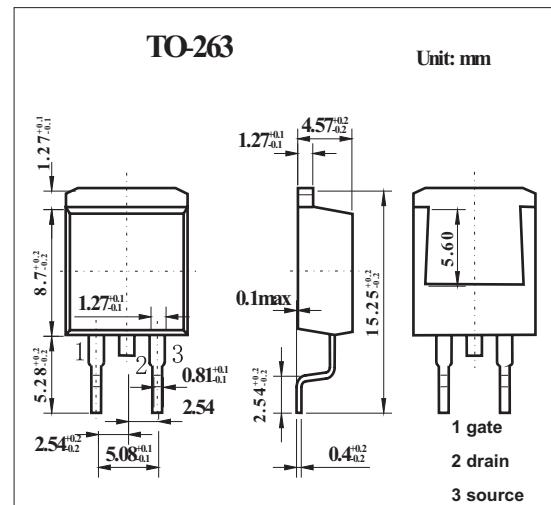


TrenchPLUS standard level FET

KUK7107-55AIE



■ Features

- Integrated temperature sensor
- ESD protection
- Q101 compliant
- Standard level compatible

■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Drain-source voltage	V _{Ds}	55	V
Drain-gate voltage IdG = 250 µA	V _{DGR}	55	V
Gate-source voltage	V _{GS}	±20	V
Drain current (DC) T _{mb} = 25°C, V _{GS} = 10 V	I _D	140	A
Drain current (DC) T _{mb} = 100°C, V _{GS} = 10 V	I _D	75	A
peak drain current *1	I _{DM}	560	A
Total power dissipation T _{mb} = 25°C	P _{tot}	272	W
gate-source clamping current (continuous)	I _{GS(CL)}	10	mA
gate-source clamping current *3		50	mA
Storage & operating temperature	T _{stg} , T _j	-55 to 175	°C
reverse drain current (DC) T _{mb} = 25°C	I _{DR}	140	A
		75	A
pulsed reverse drain current *1	I _{DRM}	560	A
non-repetitive avalanche energy *2	E _{DS(AL)S}	460	J
electrostatic discharge voltage; all pins *4	V _{ESD}	6	KV
Thermal resistance junction to mounting base	R _{th j-mb}	0.55	K/W
Thermal resistance junction to ambient	R _{th j-a}	50	K/W

* 1 T_{mb} = 25°C; pulsed; tp ≤ 10 µs;

*2 unclamped inductive load; Id = 68 A; V_{Ds} ≤ 55 V; V_{GS} = 10 V; R_{GS} = 50Ω; starting T_j = 25°C

*3 tp = 5 ms; δ = 0.01

*4 Human Body Model; C = 100 pF; R = 1.5 kΩ

KUK7107-55AIE■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
drain-source breakdown voltage	$V_{(BR)DSS}$	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$	55			V
		$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55^\circ\text{C}$	50			V
gate-source threshold voltage	$V_{GS(th)}$	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25^\circ\text{C}$	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175^\circ\text{C}$	1			V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55^\circ\text{C}$			4.4	V
Zero gate voltage drain current	I_{DSS}	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$		0.1	10	μA
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175^\circ\text{C}$			250	μA
gate-source breakdown voltage	$V_{(BR)GSS}$	$I_G = \pm 1 \text{ mA}; -55^\circ\text{C} < T_j < 175^\circ\text{C}$	20	22		V
gate-source leakage current	I_{GSS}	$V_{GS} = \pm 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25^\circ\text{C}$		22	1000	nA
		$V_{GS} = \pm 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 175^\circ\text{C}$			10	μA
drain-source on-state resistance	R_{DSon}	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25^\circ\text{C}$.	5.8	7	$\text{m}\Omega$
		$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 175^\circ\text{C}$			14	$\text{m}\Omega$
ratio of drain current to sense current	I_D/I_{sense}	$V_{GS} > 10 \text{ V}; -55^\circ\text{C} < T_j < 175^\circ\text{C}$	450	500	550	
total gate charge	$Q_g(\text{tot})$	$V_{GS} = 10 \text{ V}; V_{DD} = 44 \text{ V}; I_D = 25 \text{ A}$		116		nC
gate-to-source charge	Q_{GS}			19		nC
gate-to-drain (Miller) charge	Q_{GD}			50		nC
input capacitance	C_{iss}	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$		4500		pF
output capacitance	C_{oss}			960		pF
reverse transfer capacitance	C_{rss}			510		pF
turn-on delay time	$t_{d(on)}$	$V_{DD} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V}; R_G = 10 \Omega$		36		ns
rise time	t_r			115		ns
turn-off delay time	$t_{d(off)}$			159		ns
fall time	t_f			111		ns
internal drain inductance	L_d	measured from upper edge of drain mounting base to center of die		2.5		nH
internal source inductance	L_s	measured from source lead to source bond pad		7.5		nH
source-drain (diode forward) voltage	V_{SD}	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}$		0.85	1.2	V
reverse recovery time	t_{rr}	$I_S = 20 \text{ A}; dI/dt = -100 \text{ A}/\mu\text{s}; V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}$		80		ns
recovered charge	Q_r			200		nC